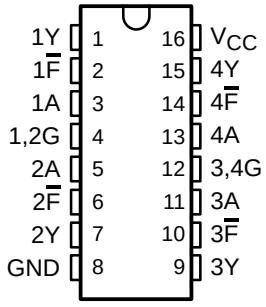
- **Meets IBM 360/370 I/O Interface Specification GA22-6974-3 (Also See SN75ALS130)**
- **Minimum Output Voltage of 3.11 V at I_{OH} = −60 mA**
- **Fault-Flag Circuit Output Signals Driver Output Fault**
- **Fault-Detection Current Limit Circuit Minimizes Power Dissipation During a Fault Condition**
- **Advanced Low-Power Schottky Circuitry**
- **Dual Common Enable**
- **Individual Fault Flags**
- **Designed to Be an Improved Replacement for the MC3481**

D OR N PACKAGE
(TOP VIEW)



FUNCTION TABLE

INPUTS		OUTPUTS	
G	**A**	**Y**	**F̄**
L	X	L	H
H	H	H	H
H	H	S	L

H = high level, L = low level,
X = irrelevant,
S = shorted to GND

description

The SN75ALS126 quadruple line driver is designed to meet the IBM 360/370 I/O specification GA22-6974-3. The output voltage is 3.11 V minimum (at I_{OH} = – 59.3 mA) over the recommended ranges of supply voltage (4.5 V to 5.95 V) and temperature. Driver outputs use a fault-detection current-limit circuit to allow high drive current but still minimize power dissipation when the output is shorted to ground. The SN75ALS126 is compatible with standard TTL logic and supply voltages.

The SN75ALS126 employs the IMPACT™ process to achieve fast switching speeds and low power dissipation. Fault-flag circuitry is designed to sense and signal a line short on any Y line. Upon detecting an output fault condition, the fault-flag circuit forces the driver output into a low state and signals a fault condition by causing the fault-flag output to go low.

The SN75ALS126 can drive a 50-Ω load as required in the IBM GA22-6974-3 specification or a 90-Ω load as used in many I/O systems. Optimum performance can be achieved when the device is used with either the SN75127, SN75128, or SN75129 line receivers.

The SN75ALS126 is characterized for operation from 0°C to 70°C.

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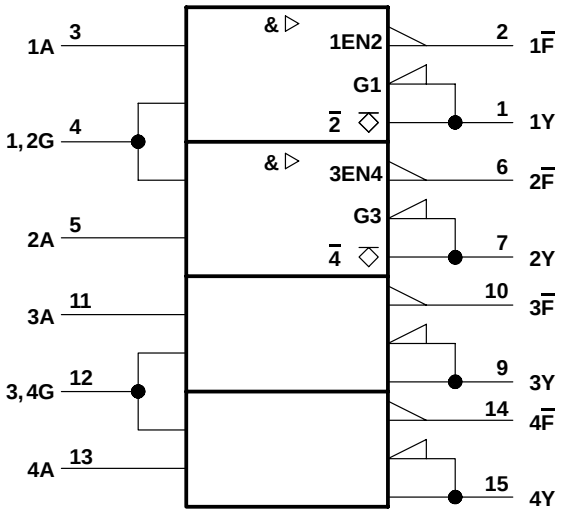
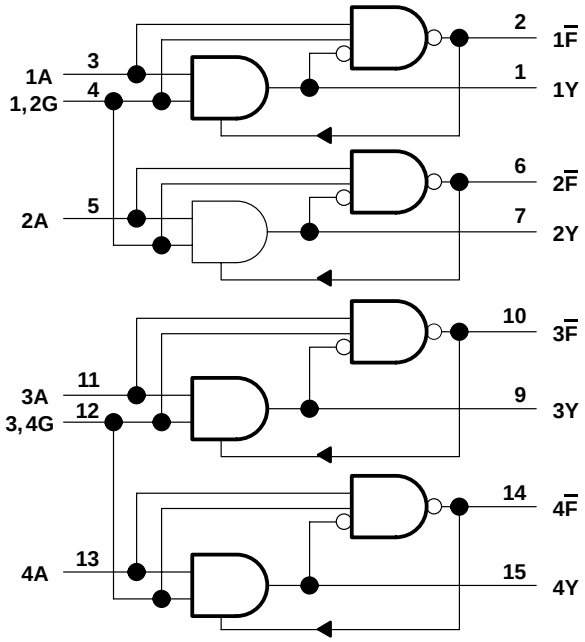
logic symbol†



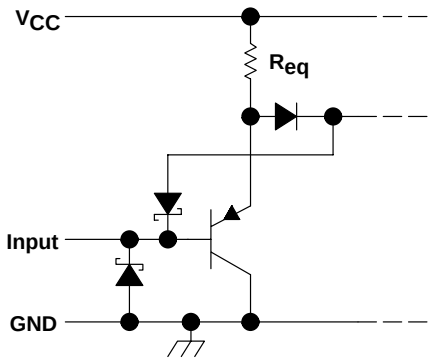
† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



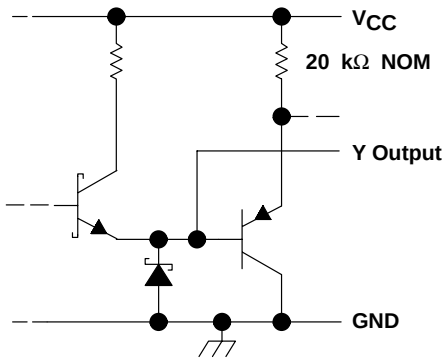
schematics of inputs and outputs

EQUIVALENT OF EACH INPUT

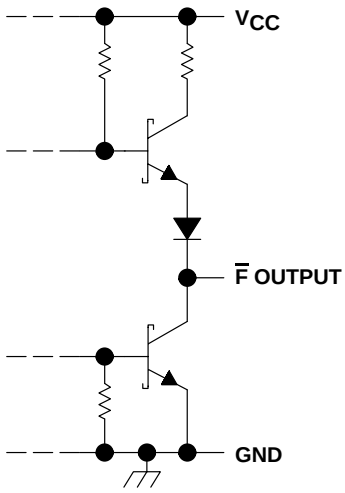


A Inputs: R_{eq} = 20 kΩ NOM
G Inputs: R_{eq} = 10 kΩ NOM

TYPICAL OF ALL Y OUTPUTS



TYPICAL OF $\overline{F}$ OUTPUT



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} . . . . . 7 V
Input voltage . . . . . 7 V
Continuous total dissipation . . . . . See Dissipation Rating Table
Operating free-air temperature range . . . . . 0°C to 70°C
Storage temperature range . . . . . – 65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds . . . . . 260°C

DISSIPATION RATING TABLE

PACKAGE	$T_A \leq 25°C$ POWER RATING	DERATING FACTOR ABOVE $T_A = 25°C$	$T_A = 70°C$ POWER RATING
D	950 mW	7.6 mW/°C	608 mW
N	1150 mW	9.2 mW/°C	736 mW

recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V_{CC}	4.5	5	5.95	V
High-level input voltage, V_{IH}	2			V
Low-level input voltage, V_{IL}			0.8	V
High-level output current, I_{OH}			– 59.3	mA
Operating free-air temperature, T_A	0		70	°C

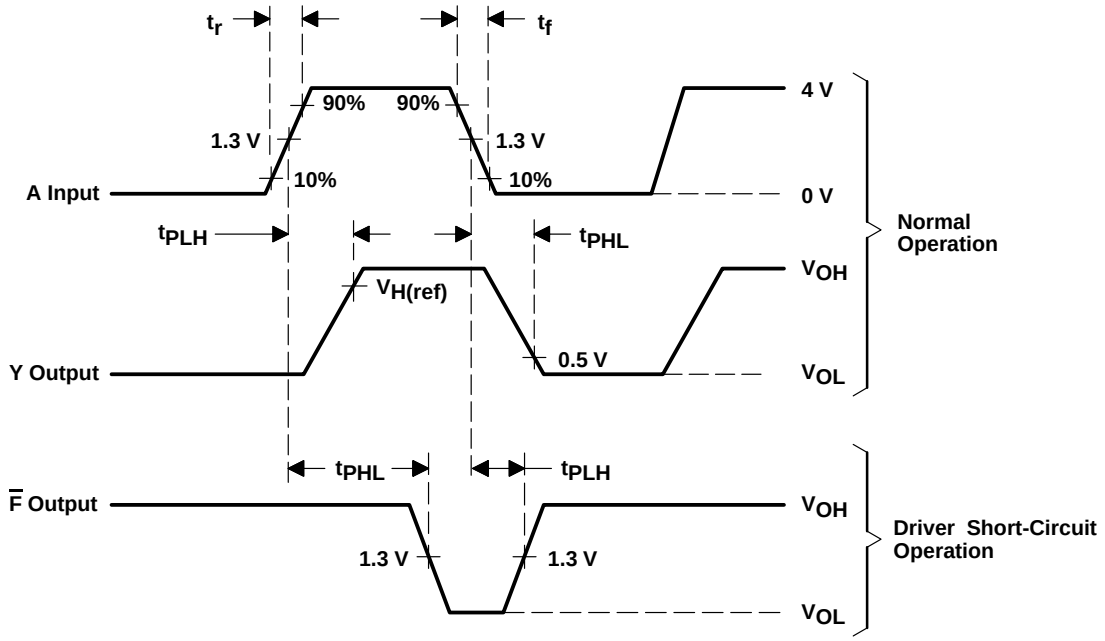
electrical characteristics over recommended operating free-air temperature range

PARAMETER			TEST CONDITIONS			MIN	MAX	UNIT
V_{IK}	Input clamp voltage	A,G	V_{CC} = 4.5 V,	I_I = – 18 mA			– 1.5	V
V_{OH}	High-level output voltage	Y	V_{CC} = 4.5 V,	I_{OH} = – 59.3 mA,	V_{IH} = 2 V	3.11		V
		Y	V_{CC} = 5.25 V,	I_{OH} = – 41 mA,	V_{IH} = 2 V	3.9		
		$\overline{F}$	V_{CC} = 4.5 V,	I_{OH} = – 400 µA,	V_{IH} = 2 V	2.5		
V_{OL}	Low-level output voltage	Y	V_{CC} = 5.5 V,	I_{OL} = – 240 µA,	V_{IL} = 0.8 V		0.15	V
		Y	V_{CC} = 5.95 V,	I_{OL} = – 1 mA,	V_{IL} = 0.8 V		0.15	
		$\overline{F}$	V_{CC} = 4.5 V,	I_{OL} = 8 mA,	Y at 0 V		0.5	
$I_{O(off)}$	Off-state output current	Y	V_{CC} = 4.5 V,	V_{IL} = 0,	V_O = 3.11 V		100	µA
		Y	V_{CC} = 0 V,	V_{IL} = 0,	V_O = 3.11 V		200	
I_I	Input current	A	V_{CC} = 4.5 V,	V_I = 5.5 V			100	µA
		G					400	
I_{IH}	High-level input current	A	V_{CC} = 4.5 V,	V_I = 2.7 V			20	µA
		G					80	
I_{IL}	Low-level input current	A	V_{CC} = 5.95 V,	V_I = 0.4 V			– 250	µA
		G					–1000	
I_{OS}	Short-circuit output	Y	V_{CC} = 5.5 V,	V_O = 0,	V_{IH} = 2.7 V		–5	mA
		$\overline{F}$	V_{CC} = 5.5 V,	V_O = 0		–15	–100	
		Y	V_{CC} = 5.95 V,	V_O = 0,	V_{IH} = 2.7 V		–5	
		$\overline{F}$	V_{CC} = 5.95 V,	V_O = 0		–15	–110	
I_{CCH}	Supply current, all outputs high		V_{CC} = 5.5 V,	No load,	V_{IH} = 2.7 V		25	mA
			V_{CC} = 5.95 V,	No load,	V_{IH} = 2.7 V		27	
I_{CCL}	Supply current, Y outputs low		V_{CC} = 5.5 V,	No load,	V_{IL} = 0.4 V		45	mA
			V_{CC} = 5.95 V,	No load,	V_{IL} = 0.4 V		47	

switching characteristics over recommended operating free-air temperature range

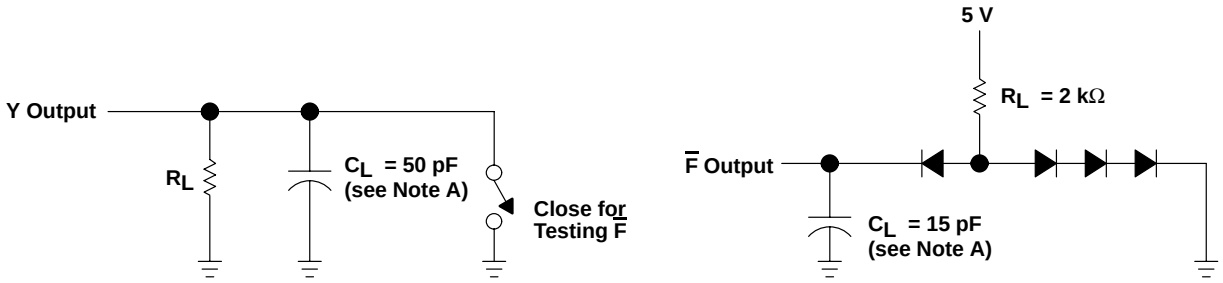
PARAMETER		FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	MAX	UNIT
t_{PLH}	Propagation delay time, low-to-high-level output	A	Y	V_{CC} = 4.5 V to 5.5 V, R_L = 50 Ω, See Figures 1 and 2	C_L = 50 pF, $V_{H(ref)}$ = 3.11 V,		30	ns
t_{PHL}	Propagation delay time, high-to-low-level output						28	ns
$\frac{t_{PLH}}{t_{PHL}}$	Ratio of propagation delay times					0.3	3	
t_{PLH}	Propagation delay time, low-to-high-level output	A	Y	V_{CC} = 5.25 V to 5.95 V, R_L = 90 Ω, See Figures 1 and 2	C_L = 50 pF, $V_{H(ref)}$ = 3.9 V,		34	ns
t_{PHL}	Propagation delay time, high-to-low-level output						34	ns
t_{PLH}	Propagation delay time, low-to-high-level output	A	$\overline{F}$	V_{CC} = 5 V, C_L = 15 pF,	R_L = 2 kΩ, See Figures 1 and 2		45	ns
t_{PHL}	Propagation delay time, high-to-low-level output						75	ns

PARAMETER MEASUREMENT INFORMATION



NOTE A: The input pulse is supplied by a generator having the following characteristics: PRR ≤ 1 MHz, duty cycle ≤ 50%, t_r ≤ 6 ns, t_f ≤ 6 ns, Z_O ≈ 50 Ω.

Figure 1. Input and Output Voltage Waveforms



NOTE A: C_L includes probe and stray capacitance.

Figure 2. Switching Characteristics Load Circuits

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